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|                                   |                    | Application Number   | 09/960,734 |                        |                    |  |
| INFORMATION DISCLOSURE            |                    |                      | URE        | Filing Date            | September 24, 2001 |  |
| STATEMENT BY APPLICANT            |                    | First Named Inventor | Klaus RINN |                        |                    |  |
| (use as many sheets as necessary) |                    |                      |            | Art Unit               | 2625               |  |
|                                   |                    |                      | v)         | Examiner Name          | Gregory M. Desire  |  |
| Sheet                             | 1                  | of                   | 2          | Attorney Docket Number | 20981/50402        |  |

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| Examiner<br>Initials* | Cite<br>No.1 | Document Number  Number-Kind Code <sup>2</sup> (if known) | Publication Date<br>MM-DD-YYYY | Name of Patentes or<br>Applicant of Cited Document | Pages, Columns, Lines, Where<br>Relevant Passages or Relevant<br>Figures Appear |
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| Examiner  | On 0:-          | Date       | 2/12/05 |
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CHADE Complete If Known Substitute for form 1449B/PTO 09/960,734 **Application Number** September 24, 2001 Filing Date INFORMATION DISCLOSURE First Named Inventor Klaus RINN STATEMENT BY APPLICANT 2625 Art Unit Gregory M. Desire **Examiner Name** (use as many sheets as necessary) 2098L/50402 2 Attorney Docket Number ٥f Sheet 2

| Examiner Initials*    Cite No.   Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.   SPIE, Vol. 3095 entitled "Advanced Mask Metrology System for up to 4Gbit DRAM" by Taro OTOTAKE et al., pp. 433-444    SPIE, Vol. 3095 entitled "Advanced Mask Metrology System for up to 4Gbit DRAM" by Taro OTOTAKE et al., pp. 433-444    IEEE Transactions on Industrial Electronics, Vo. 35, No. 1, Feb. 1988 entitled "Subpixel Edge Detection and Estimation with a Microprocessor-Controlled Line Scan Camera" by Yu-Shan LI et al., pp. 105-112    Matrox Imaging Library User Guide, Manual No. 10328-MN-0300, Aug. 9, 1995, p. 138    Im - Technisches Messen 61, (1994) 10 entited "Near-Field and Far-Field Scanning Microscopy on Features in the Sub-micrometer Range" by Heinrich GEUTHER et al., pp. 1-18    VOI BERICHTE 659, Symposium Braunschweig 3, bis No. 6, 1987 entitled "Strukturbreitenmessung mit lichtoptischen Verfahren" by W. Mirandé pp. 319-330 |   | NON PATENT LITERATURE DOCUMENTS   |   |   |
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| IEEE Transactions on Industrial Electronics, Vo. 35, No. 1, Feb. 1988 entitled "Subpixel Edge Detection and Estimation with a Microprocessor-Controlled Line Scan Camera" by Yu-Shan Li et al., pp. 105-112    Matrox Imaging Library User Guide, Manual No. 10328-MN-0300, Aug. 9, 1995, p. 138   | D   |   | RAM" by Taro OTOTAKE et al.,  |   |
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